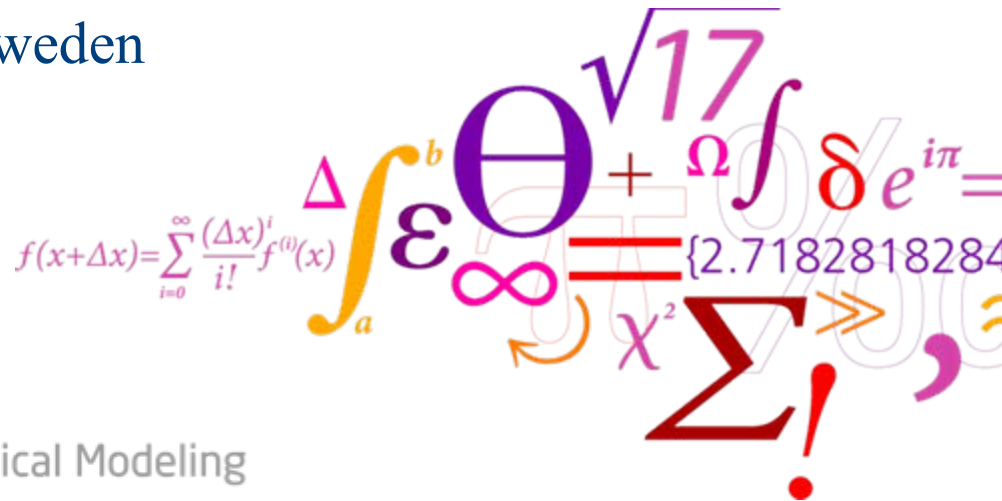


Energy/Reliability Trade-offs in Fault-Tolerant Event-Triggered Distributed Embedded Systems

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$$f(x+\Delta x) = \sum_{i=0}^{\infty} \frac{(\Delta x)^i}{i!} f^{(i)}(x)$$
$$\int_a^b \epsilon \Theta + \Omega \int \delta e^{i\pi} = \{2.7182818284\}$$
$$\chi^2 \sum !$$

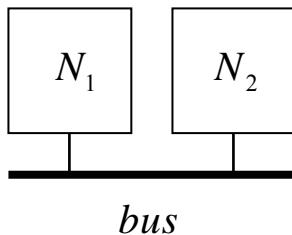
Motivation

- Newer technologies are leading to:
 - Higher power density
 - Increased likelihood of transient faults
- A lot of research on **energy/performance trade-offs** using DVFS:
 - Scaling voltage and frequency can **reduce the energy consumption**, but it **prolongs the tasks execution time**.
- We focus on **energy/reliability trade-offs** in this paper:
 - Scaling voltage and frequency can **reduce the energy consumption**, but it **increases the number of transient faults exponentially**.
 - This is orthogonal to peak temperature minimization used to increase the life-time of a system.

- **System Models and Schedulability Analysis**
 - Architecture model
 - Reliability model
 - Application model
 - Schedulability analysis
 - Power model
 - Energy/reliability trade-off model
 - **Problem Formulation**
 - Motivational Example
- **Optimization Strategy**
 - TABU search-based algorithm
- **Experimental Results**
- **Conclusion and Contributions**

Architecture Model

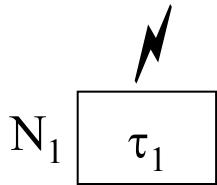
- A set of heterogeneous processing elements interconnected by a communication channel
- Each processing element might have a set of operating modes
- For each operating mode we know
(frequency: $f_i^{N_j}$, voltage: $v_i^{N_j}$, power dissipation: $p_i^{N_j}$)



	N_1			N_2		
Operating Modes	Freq. [MHz]	Volt. [V]	Power [W]	Freq. [MHz]	Volt. [V]	Power [W]
1	333	1.2	4	166	1.1	2
2	666	1.4	12	333	1.25	4.5
3	1000	1.6	25	500	1.5	11

Reliability Model

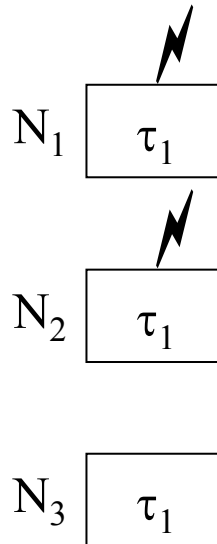
No
fault-tolerance



$$R_i = e^{-\lambda c}$$

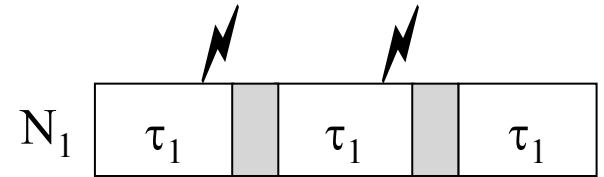
Fault-tolerance: ⚡ $k_1 = 2$

Replication



$$R_i^{rep} = 1 - \prod_{i=1}^k (1 - R_i)$$

Re-execution



$$R_i^{reex} = 1 - (1 - R_i)^{1+k}$$

- In this paper, we use $R_s = \prod_{i=1}^{|\Gamma|} R_i^{rep}$

Application Model

■ Application Model:

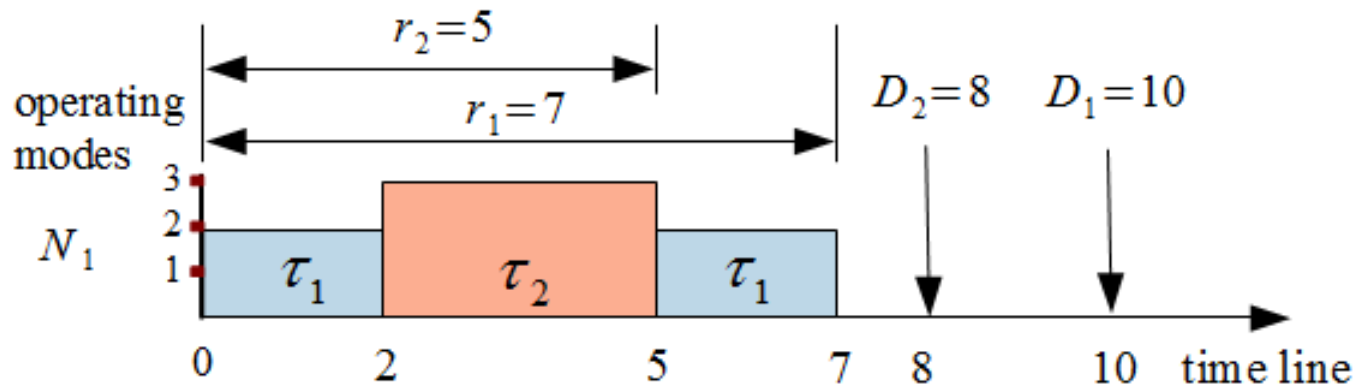
- A set of periodic tasks
- For each task τ_i , we know
 - $(C_i^{N_j}, T_i, D_i)$
 - Unique priority
 - Number of replicas k_i (critical task: $k_i > 0$, non-critical task: $k_i = 0$)
- Reliability goal R_g .
 - If reliability is lower, the no. of replicas is not enough to tolerate the faults.

Γ'	$C_i^{N_1}$	$C_i^{N_2}$	$T_i = D_i$	Priority
τ_1	7	14	50	1
τ_2	6	12	100	4
τ_3	5	10	50	2
τ_4	8	16	100	5
τ'_1	7	14	50	3
τ'_2	6	12	100	6

Schedulability Analysis

- Tasks are scheduled by **fixed-priority preemptive scheduling**.
- We use **response time analysis** to calculate the worst-case response time r_i for each task.
- We use the **degree of schedulability** r_s to measure which design alternative is “more schedulable”.

$$c_1^{l=2} = 4, c_2^{l=3} = 3$$



Energy Model

Energy consumption in **power-aware processing elements**

$$E_s = \sum_{\tau_i \in \Gamma} \left\lceil \frac{T_\Gamma}{T_i} \right\rceil \times p_l^{N_j} \times c_i^l + O$$

$\left\lceil \frac{T_\Gamma}{T_i} \right\rceil$: the number of τ_i 's jobs within the application period T_Γ

$p_l^{N_j} \times c_i^l$: the energy consumption of τ_i

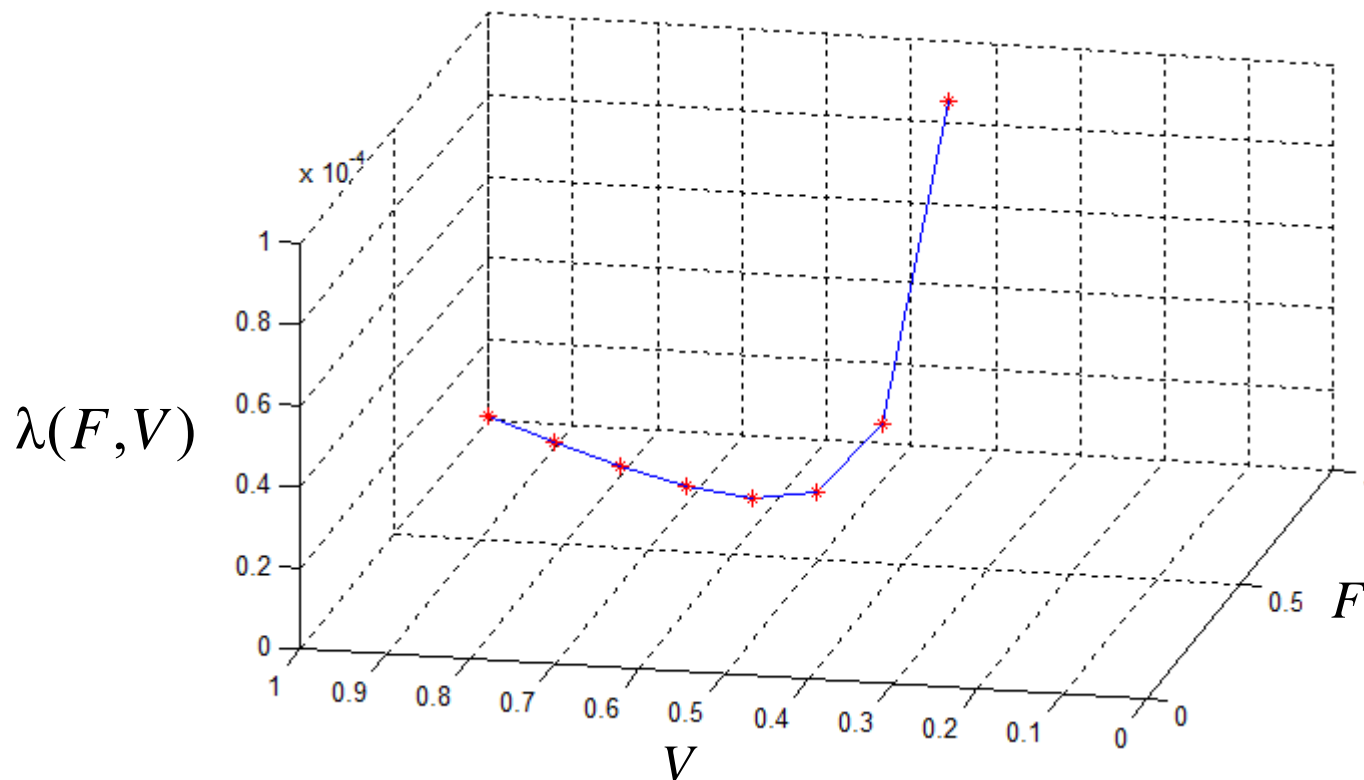
O : the sum of mode switching overheads

Energy model is from: E. Bini, G. Buttazzo and G. Lipari, “Minimizing CPU energy in realtime systems with discrete speed management”, *Embedded Computing Systems*, 31(8), 2009.

Energy/reliability Trade-off Model

The fault rate λ increases exponentially when the normalized voltage V and the normalized frequency F decreases

$$\lambda(F, V) = \lambda_0 \cdot F^\alpha \cdot 10^{-\beta V}$$



The equation is adapted from: D. Zhu and H. Aydin, "Reliability-Aware Energy Management for Periodic Real-Time Tasks", IEEE Transactions on Computers, 58(10), pp. 1382 - 1397, 2009.

Problem Formulation

- **Given:**
 - Application and architecture models
 - Reliability goal and corresponding number of replicas for each task
- **Determine offline:**
 - the **mapping** of each task to processing element
 - the **operating mode** for executing each task
- **Such that:**
 - all tasks **meet** their **timing requirements**
 - the application reliability **meets** the given **reliability goal**
 - the **energy consumption** of the system is **minimized**

Motivational Example

Application and architecture

Γ'	$C_i^{N_1}$	$C_i^{N_2}$	$T_i=D_i$	Priority	N_1			N_2			
					Operating Modes	Freq. [MHz]	Volt. [V]	Power [W]	Freq. [MHz]	Volt. [V]	Power [W]
τ_1	7	14	50	1	1	333	1.2	4	166	1.1	2
τ_2	6	12	100	4	2	666	1.4	12	333	1.25	4.5
τ_3	5	10	50	2	3	1000	1.6	25	500	1.5	11
τ_4	8	16	100	5	$\lambda_0 = 10^{-6}, \alpha = -4, \beta = -0.04$						
τ'_1	7	14	50	3							
τ'_2	6	12	100	6							

Initial solution: no voltage and frequency scaling

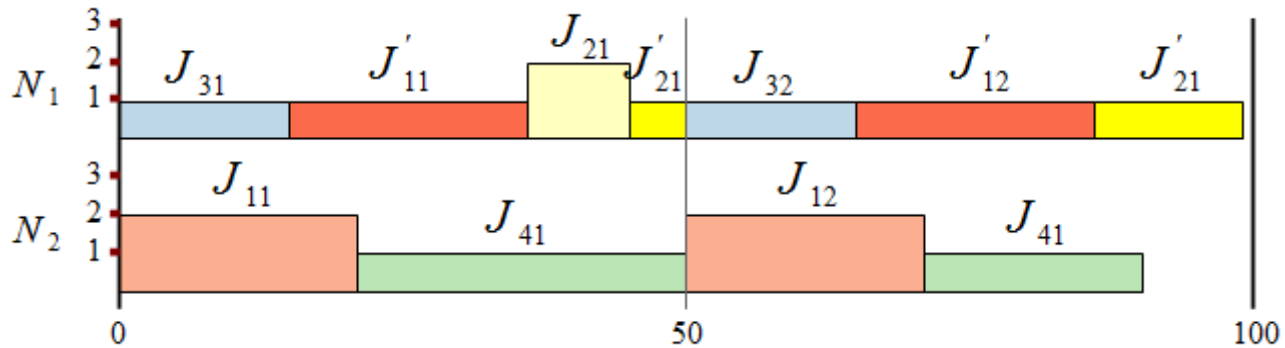
- Runs all the tasks in the maximum speed operating mode and maps the tasks on the low power PEs.
- $E_0=1312$, $R_s^0=0.999996$.

The given reliability goal: $R_g=1-10(1-R_s^0)=0.99996$

which means that we accept at most a 10 times decrease in reliability.

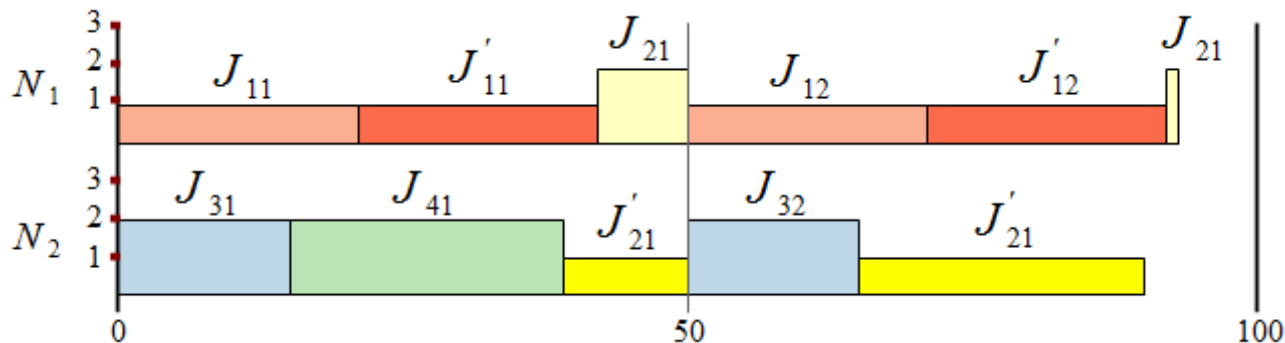
Motivational Example

Energy minimization without concern for reliability



Reduce energy by 42.58%. Prob. of failure increased by 160 times ($\gg 10$ times).

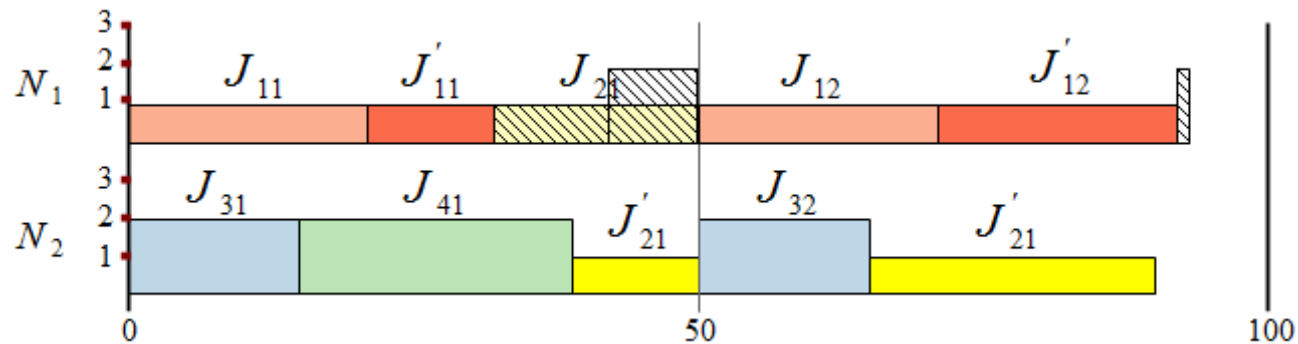
Energy/reliability trade-off optimization



Reduce energy by 42.13%. Prob. of failure increased by 7 times (< 10 times).

Energy/Reliability Trade-off at Runtime

Further energy saving in online optimization without impacting the reliability goal



Reduce energy by 50.66%. Prob. of failure increased by 10 times (= 10 times).

Optimization Strategy

- **Optimization Problem**

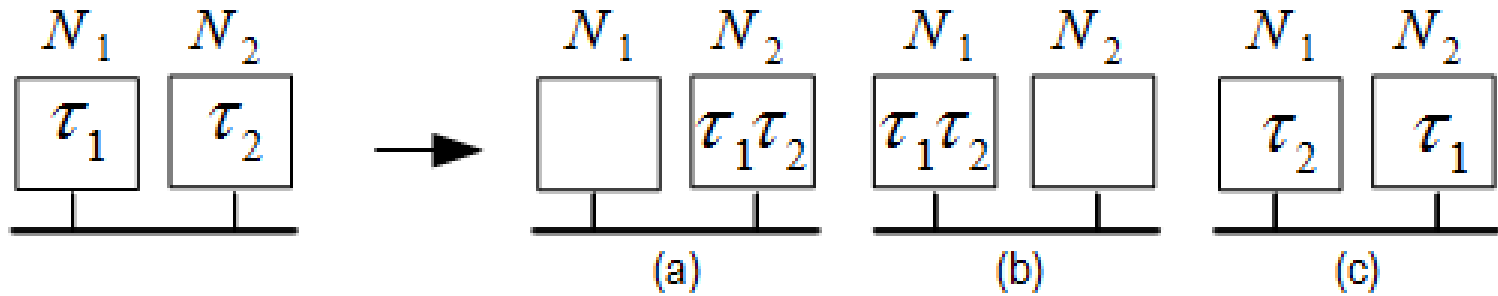
- NP-hard
- Minimize the cost function:

$$Cost(S) = \underbrace{E_S}_{\text{Energy}} + \underbrace{W_R \cdot \max(0, R_g - R_s)}_{\text{Reliability}} + \underbrace{W_r \cdot \max(0, r_s)}_{\text{Schedulability}}$$

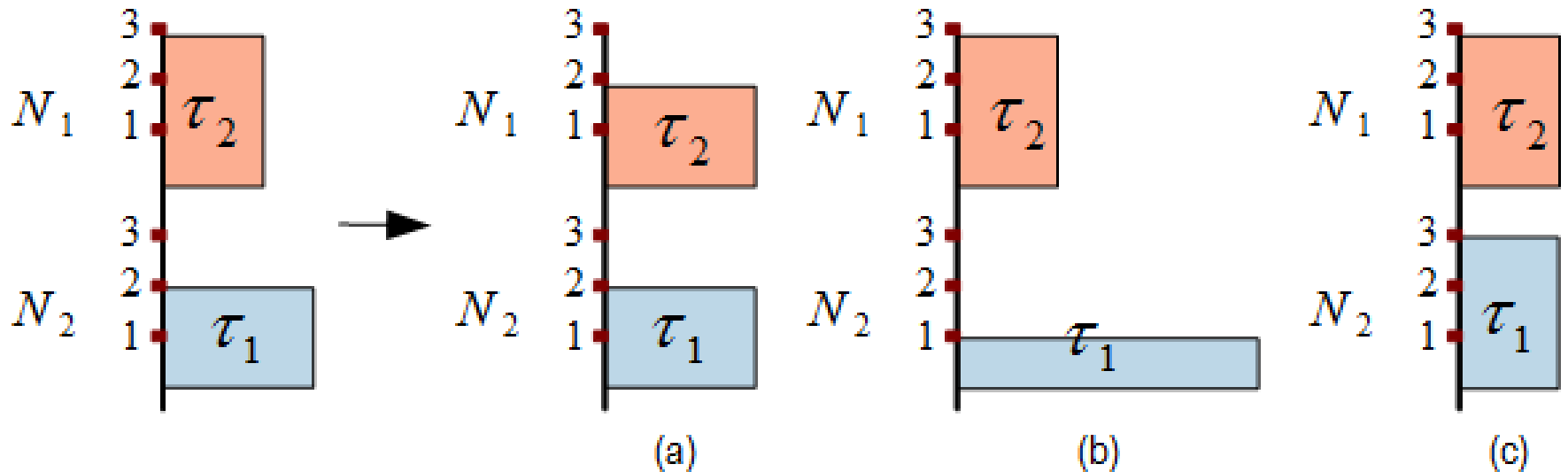
- Use a **TABU search-based algorithm** to explore the design space
 - Iteratively explores neighborhood solutions by
 - mapping moves
 - operating mode moves
 - Avoid being stuck in local optimum
 - Prevents cycling back to previously visited solutions

TABU Search-based Algorithm

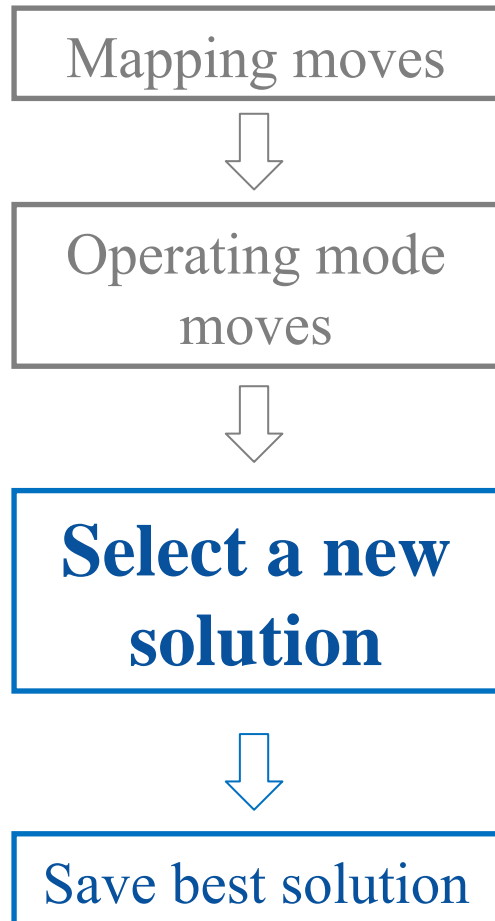
Mapping moves



Operating mode moves



TABU Search-based Algorithm



- **First attempt**
An improved solution
- **Otherwise**
Randomly select a non-improving and not-tabu solution
- **Maintenance of TABU-list**

Experimental Results

Reliability improvement for different size of systems

Test Set	Numbers of			MVFS ⁻		MVFS	
	PEs	Orig. Tasks	Repl. Tasks	θ [times]	Saved E [%]	θ [times]	Saved E [%]
1	2	8	2	166	28.23	10	24.64
2	4	31	8	112	28.56	10	25.28
3	4	42	11	137	30.47	10	26.04
4	6	63	16	104	25.92	10	21.92
5	6	84	21	57	22.78	10	20.57

$$\theta = \frac{1 - R_s}{1 - R_s^0} : \text{measures the reliability degeneration}$$

(i.e. how many times the prob. of failure increases)

MVFS⁻: optimization without concern for reliability

MVFS: energy/reliability trade-off optimization

Experimental Results

Reliability improvement as system utilization increases

Test Set	Numbers of			Initial Util. [%]	MVFS ⁻		MVFS	
	PEs	Orig. Tasks	Repl. Tasks		θ [times]	Saved E [%]	θ [times]	Saved E [%]
1	3	20	5	27.21	198	29.57	10	25.00
2	3	20	5	41.00	121	26.55	8	23.02
3	3	20	5	52.73	101	25.26	9	21.05
4	3	20	5	61.56	72	22.94	10	20.09
5	3	20	5	71.98	7	12.76	7	12.76

Experimental Results

Reliability improvement for real-life case studies

Benchmarks	Numbers of			MVFS ⁻		MVFS	
	PEs	Orig. Tasks	Repl. Tasks	θ [times]	Saved E [%]	θ [times]	Saved E [%]
networking-cords	2	13	3	141	28.01	10	20.49
auto-indust-cords	4	24	6	77	22.68	10	17.87
telecom-cords	4	30	8	129	28.16	9	19.57
3 Apps together	6	67	17	64	15.26	10	13.86
Smart-phone	2	61	16	60	18.71	9	15.23

Conclusion and Contributions

- **Conclusion:**

We are able to reduce the negative impact of energy minimization on reliability with minimal decrease in energy savings.

- **Contributions:**

- Considered energy/reliability trade-offs
 - Proposed an optimization algorithm for the energy/reliability trade-off problem